

FDH15N50 / FDP15N50 / FDB15N50

15A, 500V, 0.38 Ohm, N-Channel SMPS Power MOSFET

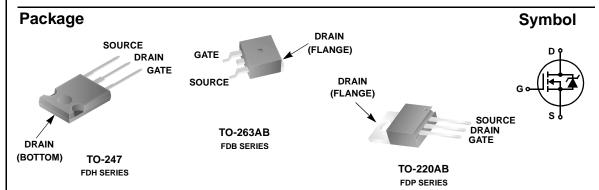
Applications

Switch Mode Power Supplies(SMPS), such as

- PFC Boost
- Two-Switch Forward Converter
- Single Switch Forward Converter
- · Flyback Converter
- Buck Converter
- · High Speed Switching

Features

- Improved Gate, Avalanche and High Reapplied dv/dt Ruggedness
- Reduced r_{DS(ON)}
- Reduced Miller Capacitance and Low Input Capacitance
- Improved Switching Speed with Low EMI
- 175°C Rated Junction Temperature



Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	500	V
V_{GS}	Gate to Source Voltage	±30	V
	Drain Current		
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$)	15	Α
I _D	Continuous ($T_C = 100^{\circ}$ C, $V_{GS} = 10V$)	11	Α
	Pulsed ¹	60	Α
	Power dissipation	300	W
P_{D}	Derate above 25°C	2	W/oC
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C
	Soldering Temperature for 10 seconds	300 (1.6mm from case)	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case	0.50	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (TO-247)	40	°C/W
$R_{\theta,JA}$	Thermal Resistance Junction to Ambient (TO-220, TO-263)	62	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDH15N50	FDH15N50	TO-247	Tube	-	30
FDP15N50	FDP15N50	TO-220	Tube	-	50
FDB15N50	FDB15N50	TO-263	330mm	24mm	800

Electrical Characteristics T_J = 25°C (unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Statics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	500	-	-	V
$\Delta B_{VDSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	Reference to 25°C, ID = 1mA	-	0.58	-	V/°C
r _{DS(ON)}	Drain to Source On-Resistance	$V_{GS} = 10V, I_D = 7.5A$	-	0.33	0.38	Ω
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0	3.4	4.0	V
lana	Zero Gate Voltage Drain Current	$V_{DS} = 500V$ $T_{C} = 25^{\circ}C$	-	-	25	μA
IDSS	Zero Gate Voltage Drain Gurrent	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250	μΛ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 30V$	-	-	±100	nA

Dynamics

9 _{fs}	Forward Transconductance	$V_{DD} = 10V, I_D = 7.5A$	10	-	-	S
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 10V,	-	33	41	nC
Q_{gs}	Gate to Source Gate Charge	V _{DS} = 400V,	-	7.2	10	nC
Q _{gd}	Gate to Drain "Miller" Charge	I _D = 15A	-	12	16	nC
t _{d(ON)}	Turn-On Delay Time	$V_{DD} = 250V,$ $I_{D} = 15A,$ $R_{G} = 6.2\Omega,$ $R_{D} = 17\Omega$	-	9	-	ns
t _r	Rise Time		-	5.4	-	ns
t _{d(OFF)}	Turn-Off Delay Time		-	26	-	ns
t _f	Fall Time		-	5	-	ns
C _{ISS}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz	-	1850	-	pF
C _{OSS}	Output Capacitance		-	230	-	pF
C _{RSS}	Reverse Transfer Capacitance		-	16	-	pF

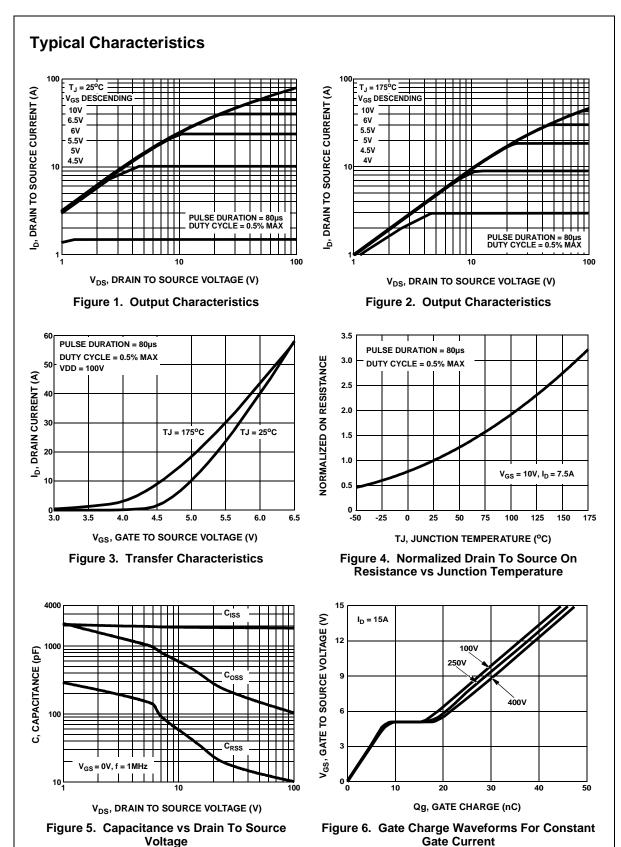
Avalanche Characteristics

E _{AS}	Single Pulse Avalanche Energy ²	760	-	-	
IAR	Avalanche Current	-	-	15	

Drain-Source Diode Characteristics

I _S	Continuous Source Current (Body Diode)	MOSFET symbol showing the	-	-	15	Α
I _{SM}	Pulsed Source Current ¹ (Body Diode)	integral reverse p-n junction diode.	-	-	60	Α
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 15A	-	0.86	1.2	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 15A$, $di_{SD}/dt = 100A/\mu s$	-	470	730	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 15A$, $di_{SD}/dt = 100A/\mu s$	-	5	6.6	μC

1: Repetitive rating; pulse width limited by maximum junction temperature 2: Starting T_J = 25°C, L = 7.0mH, I_{AS} = 15A



Voltage

Typical Characteristics SOURCE TO DRAIN CURRENT (A) $T_J = 175^{\circ}C$

<u>S</u>

V_{SD}, SOURCE TO DRAIN VOLTAGE (V)

0.7

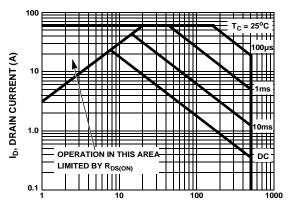
T_{.1} = 25°C

0.9

1.0

Figure 7. Body Diode Forward Voltage vs Body **Diode Current**

0.6



V_{DS}, DRAIN TO SOURCE VOLTAGE (V)



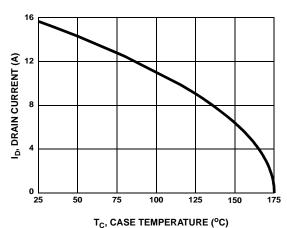
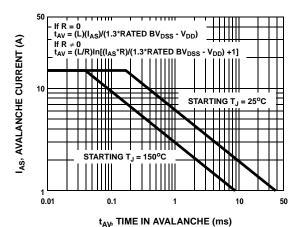
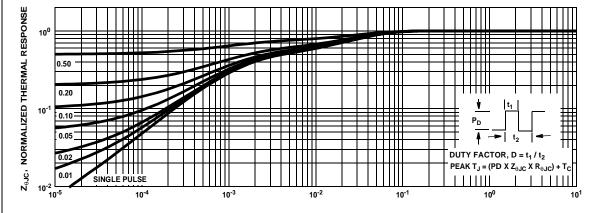


Figure 9. Maximum Drain Current vs Case







t₁, RECTANGULAR PULSE DURATION (s)

Figure 11. Normalized Transient Thermal Impedance, Junction to Case

Test Circuits and Waveforms

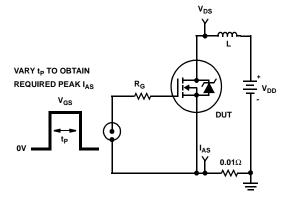


Figure 12. Unclamped Energy Test Circuit

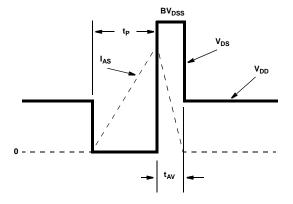


Figure 13. Unclamped Energy Waveforms

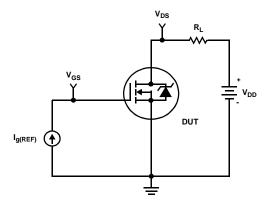


Figure 14. Gate Charge Test Circuit

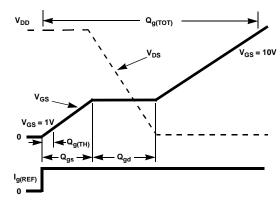


Figure 15. Gate Charge Waveforms

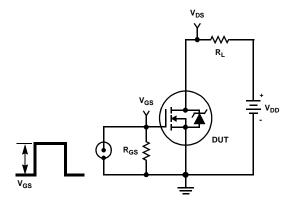


Figure 16. Switching Time Test Circuit

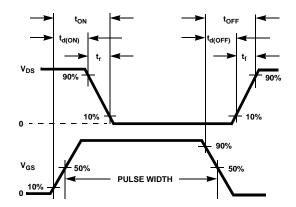


Figure 17. Switching Time Waveform

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